

FORM PTO - 1449

## INFORMATION DISCLOSURE STATEMENT

ATTY DOCKET NO.: QCS-003DV

APPLICANT: Kamieniecki

SERIAL NO.: Not yet assigned

FILING DATE: October 10, 2001

GROUP: ~~Not yet assigned~~

2881

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09/974024

## U.S. PATENT DOCUMENTS

EXAM. INIT.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
MB	4,544,887	10/01/85	Kamieniecki	324	158	10/21/82
A	4,558,660	12/17/85	Nishizawa et al.	118	725	3/16/83
	4,581,578	04/08/86	Honma et al.	324	158	01/31/84
	4,599,558	07/08/86	Castellano, Jr. et al.	324	158	12/14/83
	4,871,417	10/3/89	Nishizawa et al.	156	640	6/30/87
	5,306,671	04/26/94	Ogawa et al.			
	5,453,702	09/26/95	Goldfarb	324	765	11/29/93
	5,470,799	11/28/95	Itoh et al.	437	238	4/24/89
	5,471,293	11/28/95	Lowell et al.	356	30	02/02/94
	5,663,657	09/02/97	Lagowski et al.	324	766	09/26/94
	5,661,408	08/26/97	Kamieniecki et al.	324	765	03/01/95
MB	5,716,495	2/10/98	Butterbaugh et al.	156	643.1	3/25/96

## FOREIGN PATENT DOCUMENTS

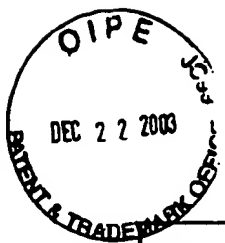
EXAM. INIT.	DOCUMENT NUMBER	DATE	COUNTRY CODE	CLASS	SUB CLASS	FILING DATE	ABSTRACT ONLY	ENGLISH LANG Y/N
MB	41 22 587	01/23/93	DE					N
MB	WO 94/23854	10/27/94	PCT					Y

## OTHER ART, JOURNAL ARTICLES, ETC.

EXAM. INIT.	OTHER DOCUMENTS: (Including Author, Title, Date, Relevant Pages, Place of Publication)
MB	Akazawa et al., "Photostimulated Evaporation of SiO <sub>2</sub> and Si <sub>3</sub> N <sub>4</sub> Films by Synchrotron Radiation and its Application for Low-Temperature Cleaning of Si Surfaces", <i>Journal of Vacuum Science and Technology</i> , Vol. 9, No. 5, September 1, 1991, pp. 2653-2661
EXAMINER	DATE CONSIDERED

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June 24, 2004



SHEET 1 OF 1

FORM PTO - 1449				ATTY DOCKET NO.: QCS-003DV					
SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT				APPLICANTS: Kamieniecki et al.					
				SERIAL NO.: 09/974,024					
				FILING DATE: October 10, 2001					
				GROUP: <del>2820</del> 2881					
U.S. PATENT DOCUMENTS									
EXAM. INIT.		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE		
<i>HW</i>	A13	3,850,508	11/26/74	Sittig et al.	356	209	11/14/72		
<i>HW</i>	A14	4,824,698	4/25/89	Jastrzebski et al.	427	255	12/23/87		
<i>HW</i>	A15	5,216,362	6/1/93	Verkuil	324	158	10/8/91		
<i>HW</i>	A16	5,581,194	12/3/96	Lowell	324	752	6/7/95		
<i>HW</i>	A17	5,977,788	11/2/99	Lagowski	324	765	7/11/97		
<i>HW</i>	A18	6,166,354	12/26/00	Hause et al.	219	390	6/16/97		
<i>HW</i>	A19	6,326,220	12/4/01	Chen et al.	438	14	11/11/00		
EXAMINER <i>Nicholas Kelly</i>				DATE CONSIDERED <i>June 22, 2004</i>					
FOREIGN PATENT DOCUMENTS									
EXAM. INIT.		DOCUMENT NUMBER	DATE	COUNTRY CODE	CLASS	SUB CLASS	FILING DATE	ABSTRACT ONLY	ENGLISH LANG Y/N
OTHER ART, JOURNAL ARTICLES, ETC.									
EXAM. INIT.	OTHER DOCUMENTS: (Including Author, Title, Date, Relevant Pages, Place of Publication)								
EXAMINER					DATE CONSIDERED				

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